

# STS3DPF30L

# DUAL P - CHANNEL 30V - 0.145Ω - 3A SO-8 STripFETTM POWER MOSFET

#### **PRELIMINARY DATA**

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	Ι <sub>D</sub>
STS3DPF30L	30 V	< 0.16 Ω	3 A

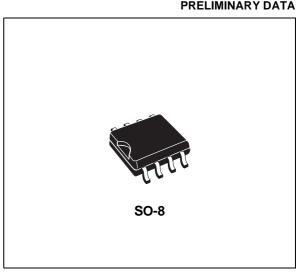
- TYPICAL  $R_{DS(on)} = 0.145 \Omega$
- STANDARD OUTLINE FOR EASY AUTOMATED SURFACE MOUNT ASSEMBLY
- LOW THRESHOLD DRIVE

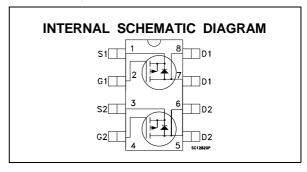
#### **DESCRIPTION**

This Power MOSFET is the second generation of STMicroelectronics unique "Single Feature Size™ " strip-based process. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

#### **APPLICATIONS**

- BATTERY MANAGMENT IN NOMADIC **EQUIPMENT**
- POWER MANAGMENT IN CELLULAR **PHONES**
- DC-DC CONVERTER





## **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source Voltage (V <sub>GS</sub> = 0)	30	V
$V_{DGR}$	Drain- gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	30	V
$V_{GS}$	Gate-source Voltage	± 20	V
I <sub>D</sub>	Drain Current (continuous) at Tc = 25 °C Single Operation Drain Current (continuous) at T <sub>c</sub> = 100 °C Single Operation	3 1.9	A A
I <sub>DM</sub> (•)	Drain Current (pulsed)	12	Α
P <sub>tot</sub>	Total Dissipation at $T_c = 25$ °C Dual Operation Total Dissipation at $T_c = 25$ °C Single Operation	2 1.6	W

<sup>(•)</sup> Pulse width limited by safe operating area

Note: For the P-CHANNEL MOSFET actual polarity of voltages and current has to be reversed

1/5 May 2000

## THERMAL DATA

R <sub>thj-amb</sub>	*Thermal Resistance Junction-ambient Single Operation	78	°C/W
	Dual Operation	62.5	°C/W
Tj	Maximum Operating Junction Temperature	150	°C
Tstg	Storage Temperature	-55 to 150	°C

(\*) Mounted on FR-4 board ( $t \le 10 \text{sec}$ )

# **ELECTRICAL CHARACTERISTICS** ( $T_{case} = 25$ $^{o}\text{C}$ unless otherwise specified) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A$ $V_{GS} = 0$	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating$ $T_c = 125  ^{\circ}C$			1 10	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			± 100	nA

## **ON (**\*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 250 \mu A$	1	1.6	2.5	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 10 V I <sub>D</sub> = 1.5 A V <sub>GS</sub> = 4.5 V I <sub>D</sub> = 1.5 A		0.145 0.18	0.16 0.19	$\Omega$
I <sub>D(on)</sub>	On State Drain Current	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $V_{GS} = 10 \text{ V}$	3			А

## **DYNAMIC**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (*)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $I_D = 3 A$		3		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V <sub>DS</sub> = 25 V f = 1 MHz V <sub>GS</sub> = 0 V		510 170 55		pF pF pF

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## **ELECTRICAL CHARACTERISTICS** (continued)

## **SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on Delay Time Rise Time	$\begin{aligned} V_{DD} &= 15 \text{ V} & I_D &= 1.5 \text{ A} \\ R_G &= 4.7 \ \Omega & V_{GS} &= 4.5 \text{ V} \\ \text{(Resistive Load, see fig. 3)} \end{aligned}$		14.5 37		ns ns
$egin{array}{c} Q_g \ Q_{gs} \ Q_{gd} \end{array}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 24 \text{ V } I_{D} = 3 \text{ A } V_{GS} = 4.5 \text{ V}$		5.5 1.7 1.8		nC nC nC

## **SWITCHING OFF**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
$t_{d(off)} \ t_{f}$	Turn-off Delay Time Fall Time	$\begin{aligned} V_{DD} &= 15 \text{ V} & I_D &= 1.5 \\ R_G &= 4.7 \ \Omega & V_{GS} &= 4.5 \\ \text{(Resistive Load, see fig. 3)} \end{aligned}$		88 23		ns ns

### SOURCE DRAIN DIODE

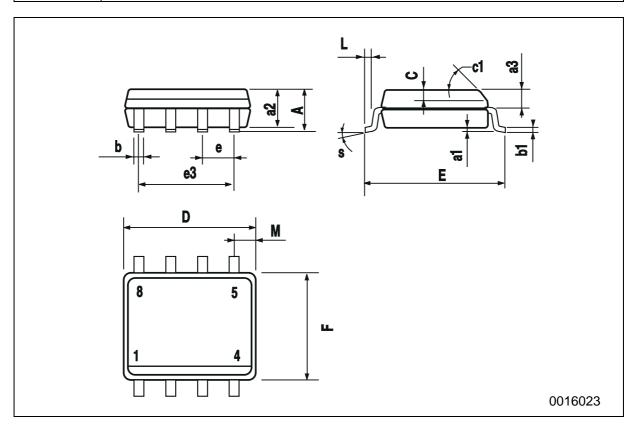
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> (•)	Source-drain Current Source-drain Current (pulsed)				3 12	A
V <sub>SD</sub> (*)	Forward On Voltage	$I_{SD} = 3 A  V_{GS} = 0$			1.2	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 3 \text{ A}$		T.B.D		ns
Q <sub>rr</sub>	Reverse Recovery Charge	(see test circuit, fig. 5)				μC
I <sub>RRM</sub>	Reverse Recovery Current					А

<sup>(\*)</sup> Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %
(•) Pulse width limited by safe operating area

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## **SO-8 MECHANICAL DATA**

DIM.		mm			inch		
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Α			1.75			0.068	
a1	0.1		0.25	0.003		0.009	
a2			1.65			0.064	
аЗ	0.65		0.85	0.025		0.033	
b	0.35		0.48	0.013		0.018	
b1	0.19		0.25	0.007		0.010	
С	0.25		0.5	0.010		0.019	
c1			45	(typ.)			
D	4.8		5.0	0.188		0.196	
E	5.8		6.2	0.228		0.244	
е		1.27			0.050		
e3		3.81			0.150		
F	3.8		4.0	0.14		0.157	
L	0.4		1.27	0.015		0.050	
М			0.6			0.023	
S			8 (r	nax.)			



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